

1                   SYNCHRONIZED MULTI-OUTPUT DIGITAL CLOCK MANAGER  
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67                   FIELD OF THE INVENTION  
89                   The present invention relates to digital clocking  
10                  circuits for digital electronics. More specifically, the  
11                  present invention relates to digital clock managers capable  
12                  of generating multiple phase-locked output clock signals of  
13                  different frequencies.14                  BACKGROUND OF THE INVENTION  
1516                  Synchronous digital systems, including board level  
17                  systems and chip level systems, rely on one or more clock  
18                  signals to synchronize elements across the system.  
19                  Typically, one or more clock signals are distributed across  
20                  the system on one or more clock lines. However, due to  
21                  various problems such as clock buffer delays, high  
22                  capacitance of heavily loaded clock lines, and propagation  
23                  delays, the edges of a clock signal in different parts of  
24                  the system may not be synchronized. The time difference  
25                  between a rising (or falling) edge in one part of the system  
26                  with the corresponding rising (or falling) edge in another  
27                  part of the system is referred to as "clock skew".  
2829                  Clock skew can cause digital systems to malfunction.  
30                  For example, it is common for circuits in digital systems to  
31                  have a first flip-flop output driving a second flip-flop  
32                  input. With a synchronized clock signal on the clock input  
33                  terminal of both flip-flops, the data in the first flip-flop  
34                  is successfully clocked into the second flip-flop. However,  
35                  if the active edge on the second flip flop is delayed by  
36                  clock skew, the second flip-flop might not capture the data

1 from the first flip-flop before the first flip-flop changes  
2 state.

3 Delay lock loops are used in digital systems to  
4 minimize clock skew. Delay lock loops typically use delay  
5 elements to synchronize the active edges of a reference  
6 clock signal in one part of the system with a feedback clock  
7 signal from a second part of the system. Figure 1 shows a  
8 block diagram of a conventional delay lock loop 100 coupled  
9 to logic circuits 190. Delay lock loop 100, which comprises  
10 a delay line 110 and a phase detector 120, receives a  
11 reference clock signal REF\_CLK and drives an output clock  
12 signal O\_CLK.

13 Delay line 110 delays reference clock signal REF\_CLK by  
14 a variable propagation delay D before supplying output clock  
15 signal O\_CLK. Thus, each clock edge of output clock signal  
16 O\_CLK lags a corresponding clock edge of reference clock  
17 signal REF\_CLK by propagation delay D (see Figure 2(a)).  
18 Phase detector 120 controls delay line 110, as described  
19 below. Delay line 110 is capable of producing a minimum  
20 propagation delay D\_MIN and a maximum propagation delay  
21 D\_MAX.

22 Before output clock signal O\_CLK reaches logic circuits  
23 190, output clock signal O\_CLK is skewed by clock skew 180.  
24 Clock skew 180 can be caused by delays in various clock  
25 buffers (not shown) or propagation delays on the clock  
26 signal line carrying output clock signal O\_CLK (e.g., due to  
27 heavy loading on the clock signal line). To distinguish  
28 output clock signal O\_CLK from the skewed version of output  
29 clock signal O\_CLK, the skewed version is referred to as  
30 skewed clock signal S\_CLK. Skewed clock signal S\_CLK drives  
31 the clock input terminals (not shown) of the clocked  
32 circuits within logic circuits 190. Skewed clock signal  
33 S\_CLK is also routed back to delay lock loop 100 on a  
34 feedback path 170. Typically, feedback path 170 is  
35 dedicated specifically to routing skewed clock signal S\_CLK  
36 to delay lock loop 110. Therefore, any propagation delay on

1 feedback path 170 is minimal and causes only negligible  
2 skewing.

3 Figure 2(a) provides a timing diagram of reference  
4 clock signal REF\_CLK, output clock signal O\_CLK, and skewed  
5 clock signal S\_CLK. All three clock signals have the same  
6 frequency F\_REF (not shown) and period P\_REF, and all are  
7 active-high (i.e., the rising edge is the active edge).  
8 Since output clock signal O\_CLK is delayed by propagation  
9 delay D, a clock edge 220 of output clock signal O\_CLK lags  
10 corresponding clock edge 210 of reference clock signal  
11 REF\_CLK by propagation delay D. Similarly, a clock edge 230  
12 of skewed clock signal S\_CLK lags corresponding clock edge  
13 220 of output clock signal O\_CLK by a propagation delay  
14 SKEW, which is the propagation delay caused by clock skew  
15 180 (Figure 1). Therefore, clock edge 230 of skewed clock  
16 signal S\_CLK lags clock edge 210 of reference clock signal  
17 REF\_CLK by a propagation delay DSKEW, which is equal to  
18 propagation delay D plus propagation delay SKEW.

19 Delay lock loop 100 controls propagation delay D by  
20 controlling delay line 110. However, delay line 110 cannot  
21 create negative delay; therefore, clock edge 230 cannot be  
22 synchronized to clock edge 210. Fortunately, clock signals  
23 are periodic signals. Therefore, delay lock loop 100 can  
24 synchronize reference clock signal REF\_CLK and skewed clock  
25 signal S\_CLK by further delaying output clock signal O\_CLK  
26 such that clock edge 240 of skewed clock signal S\_CLK is  
27 synchronized with clock edge 210 of reference clock signal  
28 REF\_CLK. As shown in Figure 2(b), propagation delay D is  
29 adjusted so that propagation delay DSKEW is equal to period  
30 P. Specifically, delay line 110 is tuned so that  
31 propagation delay D is increased until propagation delay D  
32 equals period P minus propagation delay SKEW. Although  
33 propagation delay DSKEW could be increased to any multiple  
34 of period P to achieve synchronization, most delay lock  
35 loops do not include a delay line capable of creating such a  
36 large propagation delay.

1       Phase detector 120 (Figure 1) controls delay line 110  
2 to regulate propagation delay D. The actual control  
3 mechanism for delay lock loop 100 can differ. For example,  
4 in one version of delay lock loop 100, delay line 110 starts  
5 with a propagation delay D equal to minimum propagation  
6 delay D\_MIN, after power-on or reset. Phase detector 110  
7 then increases propagation delay D until reference clock  
8 signal REF\_CLK is synchronized with skewed clock signal  
9 S\_CLK. In another system, delay lock loop 100 starts with a  
10 propagation delay D equal to the average of minimum  
11 propagation delay D\_MIN and maximum propagation delay D\_MAX,  
12 after power-on or reset. Phase detector 120 then determines  
13 whether to increase or decrease (or neither) propagation  
14 delay D to synchronize reference clock signal REF\_CLK with  
15 skewed clock signal S\_CLK. For example, phase detector 120  
16 would increase propagation delay D for the clock signals  
17 depicted in Figure 2(a). However, phase detector 120 would  
18 decrease propagation delay D for the clock signals depicted  
19 in Figure 2(c).

20      In Figure 2(c), skewed clock signal S\_CLK is said to  
21 "lag" reference clock signal REF\_CLK, because the time  
22 between a rising edge of reference clock signal REF\_CLK and  
23 the next rising edge of skewed clock signal S\_CLK is less  
24 than the time between a rising edge of skewed clock signal  
25 S\_CLK and the next rising edge of reference clock signal  
26 REF\_CLK. However, in Figure 2(a), reference clock signal  
27 REF\_CLK is said to "lag" skewed clock signal S\_CLK, because  
28 the time between a rising edge of skewed clock signal S\_CLK  
29 and the next rising edge of reference clock signal REF\_CLK  
30 is less than the time between a rising clock edge of  
31 reference clock signal REF\_CLK and the next rising clock  
32 edge of skewed clock signal S\_CLK. Alternatively, in Figure  
33 2(a) skewed clock signal S\_CLK could be said to "lead"  
34 reference clock signal REF\_CLK.

35      After synchronizing reference clock signal REF\_CLK and  
36 skewed clock signal S\_CLK, delay lock loop 100 monitors

1 reference clock signal REF\_CLK and skewed clock signal S\_CLK  
2 and adjusts propagation delay D to maintain synchronization.  
3 For example, if propagation delay SKEW increases, perhaps  
4 caused by an increase in temperature, delay lock loop 100  
5 must decrease propagation delay D to compensate.  
6 Conversely, if propagation delay SKEW decreases, perhaps  
7 caused by a decrease in temperature, delay lock loop 100  
8 must increase propagation delay D to compensate. The time  
9 in which delay lock loop 100 is attempting to first  
10 synchronize reference clock signal REF\_CLK and skewed clock  
11 signal S\_CLK, is referred to as lock acquisition. The time  
12 in which delay lock loop 100 is attempting to maintain  
13 synchronization is referred to as lock maintenance. The  
14 value of propagation delay D at the end of lock acquisition,  
15 i.e. when synchronization is initially established, is  
16 referred to as initial propagation delay ID.

17 Further complications with clock skew exists in complex  
18 digital systems, such as microprocessors and FPGAs, that  
19 have multiple clock signals at different frequencies. For  
20 example, in some microprocessors, internal circuits are  
21 clocked by a first clock signal at a first clock frequency  
22 while input/output (I/O) circuits are clocked by a second  
23 clock signal at a second clock frequency. Typically, the  
24 second clock frequency is slower than the first clock  
25 frequency.

26 Most systems use one clock generating circuit to  
27 generate a first clock signal and a specialized circuit to  
28 derive other clock signals from the first clock signal. For  
29 example, clock dividers are used to generate one or more  
30 clock signals of lower clock frequencies from a reference  
31 clock signal. Typically, clock dividers divide the  
32 frequency of the reference clock signal by an integer value.  
33 Conversely, clock multipliers are used to generate one or  
34 more clock signals of higher clock frequencies from the  
35 reference clock signal. Combining clock multipliers with  
36 clock dividers provide clocking circuits which can generate

1 one or more clock signals having frequencies that are  
2 fractional values of the frequency of the reference clock  
3 signal.

4 Thus, a clocking circuit is typically coupled to  
5 reference clock signal REF\_CLK to generate a frequency  
6 adjusted clock signal FREQ\_CLK. However, the clocking  
7 circuits add additional skew due to propagation delay and  
8 gate switching times. Consequently, frequency adjusted  
9 clock signal FREQ\_CLK may be skewed compared to both  
10 reference clock signal REF\_CLK and output clock signal  
11 O\_CLK. Hence, there is a need for a method and circuits  
12 that can compensate for skew in both an output clock signal  
13 and a frequency adjusted clock signal.

14

15 SUMMARY

16 The present invention provides a digital clock manager  
17 that generates a deskewed output clock signal as well as a  
18 deskewed frequency adjusted clock signal. Specifically, the  
19 output clock signal causes a skewed clock signal to be  
20 synchronized with a reference clock signal. The frequency  
21 adjusted clock signal is synchronized with the output clock  
22 signal during concurrences. Generally the frequency  
23 adjusted clock signal is driven to a selected clock  
24 frequency which is equal to the clock frequency of the  
25 output clock signal multiplied by a multiplier M and divided  
26 by a divider D, where M and D are natural numbers. When the  
27 frequency of the frequency adjusted clock signal is equal to  
28 the selected frequency and the frequency adjusted clock  
29 signal is in phase with the output clock signal, every Mth  
30 rising edge of the frequency adjusted clock signal aligns  
31 with a rising edge of the output clock signal. The  
32 alignments are commonly referred to as concurrences.

33 One embodiment of the digital clock manager includes a  
34 delay lock loop (DLL) and a digital frequency synthesizer  
35 (DFS). The delay lock loop is configured to generate an  
36 output clock signal that synchronizes a skewed clock signal

1 with a reference clock signal. The delay lock loop also  
2 generates a synchronizing clock signal, which is provided to  
3 the digital frequency synthesizer. The delay lock loop has  
4 a DLL output circuit that generates the output clock signal,  
5 which lags the synchronizing clock signal by a DLL output  
6 delay. In the digital frequency synthesizer, a DFS output  
7 circuit generates a frequency adjusted clock signal in which  
8 an active edge of the frequency adjusted clock signal lags  
9 an active edge of the synchronizing clock signal by a DFS  
10 output delay during a concurrence period. By matching the  
11 DLL output delay with the DFS output delay, the output clock  
12 signal and the frequency adjusted clock signals are  
13 synchronized.

14 The present invention will be more fully understood in  
15 view of the following description and drawings.

16

17 BRIEF DESCRIPTION OF THE DRAWINGS

18 Figure 1 is a block diagram of a system using a  
19 conventional delay lock loop.

20 Figures 2(a), 2(b) and 2(c) are timing diagrams for the  
21 system of Figure 1.

22 Figure 3 is a block diagram of a digital clock manager  
23 in accordance with one embodiment of the present invention.

24 Figure 4 is a block diagram of a digital clock manager  
25 in accordance with one embodiment of the present invention.

26 Figure 5 is a block diagram of a digital clock manager  
27 in accordance with one embodiment of the present invention.

28 Figure 6 is a block diagram of a system using an  
29 embodiment of a delay lock loop in accordance with the  
30 present invention.

31 Figure 7 is a timing diagram for the delay lock loop of  
32 Figure 6.

33 Figure 8 illustrates a lock window as used in  
34 accordance with one embodiment of the present invention.

1       Figure 9 is a block diagram of an embodiment of a  
2       clock phase shifter in accordance with the present  
3       invention.

4       Figure 10 is a block diagram of another embodiment of a  
5       clock phase shifter in accordance with the present  
6       invention.

7       Figure 11 is a block diagram of an output generator in  
8       accordance with the present invention.

9       Figure 12 is a state diagram for an embodiment of a  
10      controller in accordance with the present invention.

11      Figure 13 is a block diagram of a system using another  
12      embodiment of a delay lock loop in accordance with the  
13      present invention.

14      Fig. 14(a) is a block diagram of a variable clocking  
15      circuit in accordance with one embodiment of the present  
16      invention.

17      Fig. 14(b) is a timing diagram for the variable  
18      clocking circuit of Fig. 14(a).

19      Fig. 15 is schematic diagram of a variable digital  
20      oscillator in accordance with one embodiment of the present  
21      invention.

22      Fig. 16 is a timing diagram for the variable clocking  
23      circuit of Fig. 14(a) using the digital oscillator of Fig.  
24      15.

25      Fig. 17 is a block diagram of an oscillator control  
26      circuit in accordance with one embodiment of the present  
27      invention.

28      Fig. 18 is a block diagram of an initialization circuit  
29      in accordance with a second embodiment of the present  
30      invention.

31      Fig. 19 is a timing diagram for the variable clocking  
32      circuit of Fig. 14(a) using a delay line fine tuning  
33      controller.

34      Fig. 20 is a block diagram of a delay line fine tuning  
35      controller in accordance with one embodiment of the present  
36      invention.

1       Fig. 21 is a block diagram of a modulo-M delta sigma  
2       circuit in accordance with one embodiment of the present  
3       invention.

4

5       DETAILED DESCRIPTION

6       Fig. 3 is a block diagram of a digital clock manager  
7       300 in accordance with one embodiment of the present  
8       invention. Digital clock manager 300, which receives a  
9       reference clocks signal REF\_CLK and a skewed clock signal  
10      S\_CLK, generates an output clock signal O\_CLK, which causes  
11      skewed clock signal S\_CLK to be synchronized with reference  
12      clock signal REF\_CLK, and a frequency adjusted clock signal  
13      FREQ\_CLK which is phase locked with output clock signal  
14      O\_CLK during concurrences. Generally, frequency adjusted  
15      clock signal FREQ\_CLK has an adjusted frequency F\_ADJ which  
16      is equal to the frequency of output clock signal O\_CLK  
17      multiplied by a multiplier M and divided by a divider D. If  
18      frequency adjusted clock signal FREQ\_CLK is in phase with  
19      clock signal O\_CLK, every Mth rising edge of frequency  
20      adjusted clock signal FREQ\_CLK aligns with a rising edge of  
21      output clock signal O\_CLK. The alignments are commonly  
22      referred to as concurrences. Reference clock signal REF\_CLK  
23      and output clock signal O\_CLK have the same frequency. For  
24      clarity, reference frequency F\_REF is used to denote the  
25      frequency of both reference clock signal REF\_CLK and output  
26      clock signal O\_CLK.

27      The embodiment of Fig. 3 includes a delay lock loop 310  
28      and a digital frequency synthesizer 320. While specific  
29      embodiments of delay lock loop 310 and digital frequency  
30      synthesizer 320 are described below, the principles of the  
31      present invention can be adapted for use with almost any  
32      delay lock loop and any digital frequency synthesizer.  
33      Thus, the description with respect to digital clock manager  
34      300 describes delay lock loop 310 and digital frequency  
35      synthesizer 320 is in general terms. One skilled in the art  
36      can adapt the principles of the present invention to create

1 a digital clock manager with a variety of delay lock loops  
2 and digital frequency synthesizers.

3 Delay Lock Loop 310 includes DLL clocking circuit 312  
4 and DLL output circuit 314. DLL clocking circuit 312  
5 generates a synchronizing clock signal SYNCH\_CLK, which is  
6 provided to DLL output circuit 314 and DFS output circuit  
7 324 of digital frequency synthesizer 320. Generally,  
8 synchronizing clock signal SYNCH\_CLK has a frequency equal  
9 to frequency F\_REF of reference clock signal REF\_CLK and  
10 output clock signal O\_CLK. DLL output circuit 314 drives  
11 output clock signal O\_CLK. DLL output circuit 314  
12 introduces a DLL output delay 316 between synchronizing  
13 clock signal SYNCH\_CLK and output clock circuit O\_CLK.  
14 Specifically, output clock signal O\_CLK lags synchronizing  
15 clock signal SYNCH\_CLK by DLL output delay 316. DLL  
16 clocking circuit 312 and DLL output circuit 314 together  
17 synchronizes skewed clock signal S\_CLK with reference clock  
18 signal REF\_CLK. A specific embodiment of delay lock loop  
19 310 used in one embodiment of the present invention is  
20 described below.

21 Digital frequency synthesizer 320 receives synchronized  
22 clock signal SYNCH\_CLK and generates frequency adjusted  
23 clock signal FREQ\_CLK having adjusted frequency F\_ADJ, which  
24 is equal to the frequency of output clock signal O\_CLK  
25 multiplied by a multiplier M and divided by a divider D. As  
26 shown in Fig. 3, digital frequency synthesizer 320 includes  
27 a DFS clocking circuit 322 and a DFS output circuit 324.  
28 DFS output circuit 324 drives frequency adjusted clock  
29 signal FREQ\_CLK and introduces a DFS output delay 326  
30 between frequency adjusted clock signal FREQ\_CLK and  
31 synchronizing clock signal SYNCH\_CLK. Specifically, during  
32 concurrence periods of synchronizing clock signal SYNCH\_CLK  
33 with frequency adjusted clock signal FREQ\_CLK, an active  
34 edge of frequency adjusted clock signal FREQ\_CLK lags an  
35 active edge of synchronizing clock signal SYNCH\_CLK by DFS  
36 output delay 326. DFS clocking circuit 322 and DFS output

1 circuit 324 combine to perform the frequency adjustments  
2 necessary to generate frequency adjusted clock signal  
3 FREQ\_CLK.

4 Because output clock signal O\_CLK lags synchronizing  
5 clock signal SYNCH\_CLK by DLL output delay 316 and frequency  
6 adjusted clock signal FREQ\_CLK lags synchronizing clock  
7 signal SYNCH\_CLK by DFS output delay 326, frequency adjusted  
8 clock signal FREQ\_CLK can be synchronized with output clock  
9 signal O\_CLK by matching DLL output delay 316 with DFS  
10 output delay 326. Thus, in accordance with some embodiments  
11 of the invention, the components of DFS output circuit 324  
12 and DLL output circuit 314 are chosen to match DLL output  
13 delay 316 with DFS output delay 326. For example, in some  
14 embodiments of the present invention, DLL output circuit 314  
15 and DFS output circuit 324 comprise the identical  
16 components. Furthermore, in some embodiments of the present  
17 invention, the layout and routing for DLL output circuit 314  
18 closely match the layout and routing for DFS output circuit  
19 324. By matching components, layout, and routing, these  
20 embodiments of the present invention can achieve near-  
21 perfect matching between DLL output delay 316 and DFS output  
22 delay 326.

23 However, some embodiments of the present invention can  
24 not achieve suitable matching of DFS output delay 326 and  
25 DLL output delay 316. For these embodiments, additional  
26 delay circuitry can be used to synchronize output clock  
27 signal O\_CLK and frequency adjusted clock signal FREQ\_CLK.  
28 Fig. 4 is a block diagram of a digital clock manager 400  
29 using variable delay circuits 410 and 420 in accordance with  
30 one embodiment of the present invention. Because, digital  
31 clock manager 400 is similar to digital clock manager 300,  
32 similar reference numerals are used for similar elements.  
33 In addition, descriptions of the repeated elements are  
34 omitted for brevity. Variable delay circuit 410 is coupled  
35 to DLL output circuit 314 and generates output clock signal  
36 O\_CLK. Similarly, variable delay circuit 420 is coupled to

1 DFS output circuit 324 and generates frequency adjusted  
2 clock signal FREQ\_CLK.

3 In digital clock manager 400, DLL output delay 316 and  
4 DFS output delay 326 can not be adequately matched.

5 However, variable delay circuit 410, which provides  
6 additional delay to DLL output delay 316, and variable delay  
7 circuit 420, which provides additional delay to DFS output  
8 delay 326 can be used to synchronize output clock signal  
9 O\_CLK with frequency adjusted clock signal FREQ\_CLK.

10 Specifically, DLL output delay 316 plus the delay provided  
11 by variable delay circuit 410 should be matched with DFS  
12 output delay 326 plus the delay provided by variable delay  
13 circuit 420. In many embodiments of the present invention,  
14 delay match can be achieved using only one of variable delay  
15 circuits 410 or 420. Therefore, these embodiments would not  
16 need to include both variable delay circuit 410 and variable  
17 delay circuit 420.

18 Fig. 5 is a block diagram of a digital clock manager  
19 500 in accordance with one embodiment of the present  
20 invention. Because, digital clock manager 500 is similar to  
21 digital clock manager 300, similar reference numerals are  
22 used for similar elements. In addition, descriptions of the  
23 repeated elements are omitted for brevity. Digital clock  
24 manager 500 reduces the time required to generate frequency  
25 adjusted clock signal FREQ\_CLK as compared to digital clock  
26 manager 300. As is well known in the art, delay lock loops  
27 operate in a lock acquisition mode prior to generating a  
28 stable output clock signal. Similarly, digital frequency  
29 synthesizers operate in various frequency search phases  
30 prior to generating a stable frequency adjusted clock  
31 signal. In digital clock manager 300, delay lock loop 310  
32 must first undergo a lock acquisition mode to generate  
33 synchronizing clock signal SYNCH\_CLK. Then digital  
34 frequency synthesizer must undergo various frequency search  
35 phases prior to generating frequency adjusted clock signal  
36 FREQ\_CLK.

1        However, in digital clock manager 500, lock acquisition  
2        by delay lock loop 310 and frequency search phases by  
3        digital frequency synthesizer 320 can occur simultaneously  
4        to reduce the time necessary to generate output clock signal  
5        O\_CLK and frequency adjusted clock signal FREQ\_CLK.  
6        Specifically, digital clock manager 500 includes a  
7        multiplexer 510, having a first input terminal coupled to  
8        receive reference clock signal REF\_CLK, a second input  
9        terminal coupled to receive synchronizing clock signal  
10       SYNCH\_CLK and an output terminal coupled to digital  
11       frequency synthesizer 320. Multiplexer 510 is controlled by  
12       a clock transition control signal CLK\_TRAN from digital  
13       frequency synthesizer 320. Clock transition control signal  
14       CLK\_TRAN is driven to an inactive state while delay locked  
15       loop is performing lock acquisition or digital frequency  
16       synthesizer 320 is not ready for a clock transition. If  
17       clock transition control signal is in the inactive state,  
18       multiplexer 510 couples reference clock signal REF\_CLK to  
19       digital frequency synthesizer 320.

20       Because reference clock signal REF\_CLK is already at  
21       reference frequency F\_REF, digital frequency synthesizer 320  
22       can perform the required frequency search phases using  
23       reference clock signal REF\_CLK. After delay lock loop 310  
24       finishes lock acquisition, a control signal DLL\_LOCKED is  
25       driven to an active state (e.g., logic high) signaling  
26       digital frequency synthesizer 320 that delay lock loop 310  
27       has completed lock acquisition. Then, when digital  
28       frequency synthesizer is ready for transitioning to  
29       synchronizing clock signal SYNCH\_CLK, clock transition  
30       control signal CLK\_TRAN is driven to the active state, which  
31       causes synchronizing clock signal SYNCH\_CLK to be provided  
32       to digital frequency synthesizer 320. For example, in some  
33       embodiments of the present invention, digital frequency  
34       synthesizer 320 completes a frequency search phase prior to  
35       driving control signal CLK\_TRAN to select synchronizing  
36       clock signal SYNCH\_CLK. Furthermore, in some embodiments of

1 the present invention, digital frequency synthesizer 320 is  
2 halted prior to switching from reference clock signal  
3 REF\_CLK to synchronizing clock signal SYNCH\_CLK and then  
4 restarted. Thus, digital clock manager 500 reduces the time  
5 required to generate frequency adjusted clock signal  
6 FREQ\_CLK by allowing acquisition lock by delay lock loop 310  
7 and frequency searches by digital frequency synthesizer 320  
8 to operate simultaneously.

9 Figure 6 is a block diagram of a system using a delay  
10 lock loop 600 in accordance with one embodiment of the  
11 present invention. Delay lock loop 600 comprises a delay  
12 line 610, a clock phase shifter 650, a controller 630, an  
13 output generator 640, and a phase detector 620. Delay lock  
14 loop 600 receives reference clock signal REF\_CLK on a  
15 reference input terminal 602 and generates output clock  
16 signal O\_CLK on output terminal 604. As explained above  
17 with respect to Figure 1, output clock signal O\_CLK is  
18 skewed by clock skew 180 into skewed clock signal S\_CLK,  
19 which clocks logic circuits 190. Skewed clock signal S\_CLK  
20 is also fed back to a feedback terminal 606 of delay lock  
21 loop 600 on feedback path 170.

22 Within delay lock loop 600, reference clock signal  
23 REF\_CLK is delayed by delay line 610 to generate delayed  
24 clock signal D\_CLK. Delayed clock signal D\_CLK is delayed  
25 from clock signal REF\_CLK by a propagation delay D in delay  
26 line 610. One embodiment of delay lock loop 600 uses an  
27 adjustable delay line described in U.S. Patent Application  
28 Serial No. 09/102,704 (Attorney Docket No. X-440), entitled  
29 "Glitchless Delay Line Using Gray Code Multiplexer" by  
30 Andrew K. Percey, which is incorporated herein by reference.  
31 However, other adjustable delay lines can also be used with  
32 delay lock loop 600. Delayed clock signal D\_CLK is provided  
33 to an input terminal of a clock phase shifter 650 and to an  
34 input terminal of an output generator 640. Delayed clock  
35 signal D\_CLK is also provided to digital frequency  
36 synthesizer 320 as synchronizing clock signal SYNCH\_CLK.

1       Clock phase shifter 650 generates one or more phase-  
2       shifted clock signals P\_CLK\_1 to P\_CLK\_N-1, where N is a  
3       positive integer. In one embodiment, phase-shifted clock  
4       signal P\_CLK\_1 is phase-shifted by  $360/N$  degrees from  
5       delayed clock signal D\_CLK. Phase-shifted clock signal  
6       P\_CLK\_2 is phase-shifted by  $2*(360/N)$  degrees. Phase-  
7       shifted clock signal P\_CLK\_N-1 is phase-shifted by  
8        $(N-1)*(360/N)$  degrees. Thus, in general a phase-shifted  
9       clock signal P\_CLK\_Z is phase-shifted by  $Z*(360/N)$ , where Z  
10      is an integer between 1 and (N-1), inclusive. Delayed clock  
11      signal D\_CLK can be considered a phase-shifted clock signal  
12      P\_CLK\_0 since delayed clock signal D\_CLK has a 0 degree  
13      phase shift from itself. Further, in some embodiments of  
14      delay lock loop 600, clock phase shifter 650 generates a  
15      phase-shifted signal P\_CLK\_N that has the same phase and  
16      frequency as delayed clock signal D\_CLK.

17      Thus, in an embodiment of clock phase shifter 650 where  
18      N is equal to four, phase-shifted clock signal P\_CLK\_1 is  
19      phase-shifted 90 degrees from delayed clock signal D\_CLK.  
20      It logically follows that phase-shifted clock signal P\_CLK\_2  
21      is phase-shifted by 180 degrees from delayed clock signal  
22      D\_CLK and phase-shifted clock signal P\_CLK\_3 is phase-  
23      shifted by 270 degrees from delayed clock signal D\_CLK.  
24      However, the principles of the present invention are also  
25      suitable for other embodiments of clock phase shifter 650  
26      using other patterns of phase shifting between the phase-  
27      shifted clock signals.

28      Phase shifting is a concept in the frequency domain of  
29      a clock signal. The equivalent of phase shifting in the  
30      time domain is delaying the clock signal. Specifically, if  
31      a first clock signal is phase-shifted from a second clock  
32      signal by X degrees, the first clock signal is delayed by  
33       $X*(P/360)$ , where P is the period of the first and second  
34      clock signals. Thus, if phase-shifted clock signal P\_CLK\_1  
35      is phase-shifted 90 degrees from delayed clock signal D\_CLK,

1 phase-shifted clock signal P\_CLK\_1 is delayed by one-fourth  
2 of the period of delayed clock signal D\_CLK. To distinguish  
3 delays caused by phase shifting from other propagation  
4 delays, delays caused by phase shifting are referred to as  
5 phase-shifted delays P\_D\_Z. Since a phase-shifted clock  
6 signal P\_CLK\_Z is phase-shifted by  $Z*(360/N)$  degrees, phase-  
7 shifted clock signal P\_CLK\_Z has a phase-shifted delay P\_D\_Z  
8 equal to  $Z*(P/N)$ , where Z is an integer between 1 and (N-1),  
9 inclusive.

10 Figure 7 illustrates for a timing diagram for delay  
11 lock loop 600 (Figure 6) wherein N equals 4. Specifically,  
12 clock phase shifter 650 generates phase-shifted clock signal  
13 P\_CLK\_1 90 degrees out of phase with delayed clock signal  
14 D\_CLK. Thus, phase-shifted clock signal P\_CLK\_1 is delayed  
15 by one-fourth of clock period P. Clock phase shifter 650  
16 generates phase-shifted clock signal P\_CLK\_2 180 degrees out  
17 of phase with delayed clock signal D\_CLK. Thus, phase-  
18 shifted clock signal P\_CLK\_2 is delayed by half of clock  
19 period P. Finally, clock phase shifter 650 generates phase-  
20 shifted clock signal P\_CLK\_3 270 degrees out of phase with  
21 delayed clock signal D\_CLK. Thus, phase-shifted clock  
22 signal P\_CLK\_3 is delayed by three-fourths of clock period  
23 P.

24 Returning to Figure 6, clock phase shifter 650 provides  
25 the phase-shifted clock signals to various input terminals  
26 of output generator 640. In some embodiments of delay lock  
27 loop 600, clock phase shifter 650 can be configured using  
28 one or more configuration signals CFG on an optional  
29 configuration bus 660. An embodiment of clock phase shifter  
30 650 that is configured by configuration signals CFG is  
31 described below with respect to Figure 10. Configuration  
32 signals CFG are received on configuration terminals 608 and  
33 are routed to clock phase shifter 650 and controller 630 by  
34 configuration bus 660. Output generator 640 selects either  
35 delayed clock signal D\_CLK or one of the phase-shifted clock  
36 signals to provide as output clock signal O\_CLK as dictated

1 by controller 630 (described below). For embodiments of  
2 delay lock loop 600 in which clock phase shifter 650  
3 provides phase-shifted clock signal P\_CLK\_N, output  
4 generator 640 can use phase-shifted clock signal P\_CLK\_N in  
5 place of delayed clock signal D\_CLK. Controller 630  
6 controls output generator 640.

7 Controller 630 receives phase information regarding  
8 reference clock signal REF\_CLK and skewed clock signal S\_CLK  
9 from phase detector 620. Specifically, phase detector 620  
10 informs controller 630 whether propagation delay D from  
11 delay line 610 should be increased or decreased to achieve  
12 synchronization of skewed clock signal S\_CLK with reference  
13 clock signal REF\_CLK. For embodiments of phase detector 620  
14 that only determine whether to increase or decrease  
15 propagation delay D, a jitter filter (not shown) can be used  
16 to reduce clock jitter. In one embodiment, the jitter  
17 filter is an up/down counter (not shown) that decrements by  
18 one if propagation delay D should be decreased and  
19 increments by one if propagation delay D should be  
20 increased. However, propagation delay D is not adjusted  
21 until the up/down counter reaches 0 or some other  
22 predetermined number. When propagation delay D is adjusted,  
23 the up/down counter is reset to one-half the maximum value.  
24 In other embodiments, phase detector 620 calculates the  
25 amount propagation delay D should be increased or decreased.  
26 During lock acquisition, controller 630 attempts to  
27 synchronize skewed clock signal S\_CLK with reference clock  
28 signal REF\_CLK so that initial propagation delay ID of  
29 propagation delay D is within a lock window W.

30 Figure 8 illustrates the concepts of lock window W. As  
31 explained above, propagation delay D must be between minimum  
32 propagation delay D\_MIN and maximum propagation delay D\_MAX.  
33 Typical values for D\_MIN and D\_MAX are 3.2 nanoseconds and  
34 46.8 nanoseconds, respectively. During lock acquisition,  
35 controller 630 ensures that initial propagation delay ID of  
36 propagation delay D is within lock window W. Specifically,

1 when synchronization is first established initial  
2 propagation delay ID must be between lock window minimum  
3 W\_MIN and lock window maximum W\_MAX. The limits on lock  
4 window W are set to guarantee that once delay lock loop 600  
5 completes locks acquisition, delay lock loop 600 can  
6 maintain synchronization as long as the system containing  
7 delay lock loop 600 operates within the design guidelines of  
8 the system.

9 For example, the system containing delay lock loop 600  
10 generally can operate in a range of operating conditions.  
11 The range of operating conditions includes a maximum extreme  
12 condition in which propagation delay SKEW is maximized at a  
13 propagation delay value SKEW\_MAX. Similarly, the range of  
14 operating conditions also includes a minimum extreme  
15 condition in which propagation delay SKEW is minimized at a  
16 propagation delay value SKEW\_MIN. Thus, the maximum change  
17 (DELTA\_SKEW) in propagation delay SKEW during operation of  
18 the system is equal to propagation delay value SKEW\_MAX  
19 minus propagation delay value SKEW\_MIN (i.e., DELTA\_SKEW =  
20 SKEW\_MAX - SKEW\_MIN). For maximum protection during lock  
21 maintenance, lock window minimum W\_MIN can be equal to  
22 minimum propagation delay D\_MIN plus DELTA\_SKEW. Similarly,  
23 lock window maximum W\_MAX can be equal to maximum  
24 propagation delay D\_MAX minus DELTA\_SKEW. In one embodiment  
25 of the present invention, lock window minimum W\_MIN is equal  
26 to approximately 16.5% of maximum propagation delay D\_MAX  
27 and lock window maximum W\_MAX is equal to approximately  
28 67.8% of maximum propagation delay D\_MAX.

29 As explained above with respect to Figure 1, for a  
30 conventional delay lock loop synchronization of skewed clock  
31 signal S\_CLK with reference clock signal REF\_CLK is achieved  
32 when propagation delay D plus propagation delay SKEW is  
33 equal to a multiple of period P. In equation form:

$$34 \quad D + SKEW = MULT(P) \quad (1)$$

1 where  $MULT(P)$  refers to a multiple of  $P$ . Usually, the  
2 smallest multiple of  $P$  greater than  $SKEW$  is used.

3 With delay lock loop 600, controller 630 can also use  
4 the delays from the phase-shifted clock signals. Thus delay  
5 lock loop 600 can achieve synchronization if propagation  
6 delay  $D$  plus a phase-shifted delay  $P_D$  from a phase-shifted  
7 clock signal plus propagation delay  $SKEW$  is a multiple of  
8 period  $P$ . In equation form:

9

$$10 D + P_D_Z + SKEW = MULT(P) \quad (2)$$

11

12 where  $P_D_Z$  refers to a phase-shifted delay from phase-  
13 shifted clock signal  $P_{CLK\_Z}$ . Usually, the smallest  
14 multiple of  $P$  greater than propagation delay  $SKEW$  plus  
15 phase-shifted delay  $P_D_Z$  is used. As explained above with  
16 respect to Figure 6, in one embodiment of clock phase  
17 shifter 650 phase-shifted delay  $P_D_Z$  of a phase-shifted  
18 clock signal  $P_{CLK\_Z}$  is equal to  $Z*(P/N)$ , where  $Z$  is an  
19 integer between 0 and  $(N-1)$ , inclusive. If  $Z$  is equal to 0,  
20 controller 630 causes output generator 640 to use delayed  
21 clock signal  $D_{CLK}$  as output clock signal  $O_{CLK}$ . Thus,  
22 phase-shifted delay  $P_D_0$  is equal to 0.

23 For clarity, initial delay  $ID$  can be referred to  
24 initial delay  $ID_0$  if output generator 640 uses delayed  
25 clock signal  $D_{CLK}$  for output clock signal  $O_{CLK}$ .  
26 Similarly, initial delay  $ID$  can be referred to as initial  
27 delay  $ID_Z$ , if output generator 640 uses phase-shifted clock  
28 signal  $P_{CLK\_Z}$  for output clock signal  $O_{CLK}$ , where  $Z$  is a  
29 positive integer between 1 and  $(N-1)$ , inclusive. Thus, at  
30 the end of lock acquisition, equation (2) can be rewritten  
31 as:

$$32 ID_Z + P_D_Z + SKEW = MULT(P) \quad (3)$$

33

34 Re-arranging equation (3) provides:

$$1 \quad \text{ID\_Z} = \text{MULT(P)} - \text{SKEW} - \text{P\_D\_Z} \quad (4)$$

3 and substituting  $Z^*(P/N)$  for  $P_DZ$  provides:

$$ID_Z = \text{MULT}(P) - \text{SKEW} - Z^*(P/N) \quad (5)$$

7     Usually, the smallest multiple of P that results in a  
8     positive initial delay ID\_Z is used. In situations where  
9     initial delay ID\_Z is less than minimum propagation delay  
10    D\_MIN or greater than maximum propagation delay D\_MAX, delay  
11    lock loop 600 cannot synchronize skewed clock signal S\_CLK  
12    with reference clock signal REF\_CLK using phase-shifted  
13    clock signal P\_CLK\_Z.

Because controller 630 can select any one of phase-shifted clock signals P\_CLK\_Z to drive output clock signal O\_CLK, controller 630 can select from N initial delay values. The possible initial delay values range from a minimum offset value (MULT(P)-SKEW) to a maximum value (MULT(P)-SKEW) & (N-1)/N period P). The difference between each initial delay value is period P divided by N. For example, if N equals four, period P equals 40 nanoseconds, and propagation delay SKEW equals 25 nanoseconds; then initial delays ID\_0, ID\_1, ID\_2, and ID\_3 equal 15 nanoseconds, 5 nanoseconds, 35 nanoseconds, and 25 nanoseconds, respectively (as calculated using equation (5)). If N equals four, period P equals 40 nanoseconds, and propagation delay SKEW equals 55 nanoseconds; then initial delays ID\_0, ID\_1, ID\_2, and ID\_3 equal 25 nanoseconds, 15 nanoseconds, 5 nanoseconds, and 35 nanoseconds, respectively. Thus, controller 630 is likely to find one or more initial delay values within lock window W. If more than one initial delay value is within lock window W, controller 630 can select any one of the initial delay values within lock window W.

35. Some embodiments of controller 630 can perform the  
36. calculations described above to determine which phase-

1 shifted clock signal P\_CLK\_Z to use. However, other  
2 embodiments use trial and error to determine which phase-  
3 shifted clock signal P\_CLK\_Z to use. An embodiment of  
4 controller 630 that uses trial and error is described below  
5 with respect to Figure 12.

6 Figure 9 illustrates one embodiment of clock phase  
7 shifter 650 of Figure 6. The embodiment of clock phase  
8 shifter 650 in Figure 9 comprises a phase detector 920 and a  
9 plurality of delay lines 910\_1 to 910\_N. Delay lines 910\_1  
10 to 910\_N are coupled in series. The input terminal of delay  
11 line 910\_1 receives an input clock signal such as delayed  
12 clock signal D\_CLK (Figure 6). The output terminal of delay  
13 line 910\_N is coupled to an input terminal of phase detector  
14 920. Phase detector 920 also receives input clock signal  
15 D\_CLK on another input terminal. Phase detector 920  
16 controls all the delay lines in parallel via control line  
17 925, and each delay line provides the same amount of  
18 propagation delay. Consequently, input clock signal D\_CLK  
19 and the clock signal P\_CLK-N on the output terminal of delay  
20 line 910\_N are synchronized, i.e., in phase. Further, phase  
21 detector 920 causes the total propagation delay generated by  
22 delay lines 910\_1 to 910\_N to be equal to one period P of  
23 the input clock. Thus, each delay line provides a  
24 propagation delay of P/N. Thus, the output terminal of  
25 delay line 910\_1 provides a clock signal that is delayed  
26 from the input clock signal by P/N whereas the output  
27 terminal of delay line 910\_2 provides a clock signal that is  
28 delayed from the input clock signal by 2\*P/N. In general,  
29 the output terminal of delay line 910\_Z provides a clock  
30 signal that is delayed from the input clock signal by Z\*P/N,  
31 where Z is an integer between 1 and N-1, inclusive.  
32 Accordingly, if the input clock signal is delayed clock  
33 signal D\_CLK, the output terminals of delay lines 910\_1 to  
34 910\_N-1 provide phase-shifted clock signals P\_CLK\_1 to  
35 P\_CLK\_N-1, respectively. Some embodiments of clock phase  
36 shifter 650 also generate a clock signal P\_CLK\_N on the

1       output terminal of delay line 910\_N that has the same phase  
2       as delayed clock signal D\_CLK.

3       Figure 10 shows a configurable embodiment of clock  
4       phase shifter 650 of Figure 6. Specifically, the clock  
5       phase shifter of Figure 10 can be configured in a first mode  
6       to produce three phase-shifted clock signals that are 90  
7       degrees, 180 degrees, and 270 degrees out of phase with an  
8       input clock signal. In a second mode, the clock phase  
9       shifter of Figure 10 produces a single phase-shifted clock  
10      signal that is 180 degrees out of phase with the input clock  
11      signal. The clock phase shifter of Figure 10 comprises a  
12      phase detector 1020, delay lines 1010\_1, 1010\_2, 1010\_3, and  
13      1010\_4, and multiplexers 1030\_1, 1030\_2, 1030\_3, and 1030\_4.  
14      A configuration line 1040 is coupled to the select terminal  
15      of multiplexers 1030\_1 to 1030\_4.

16      The input terminal of delay line 1010\_1 is coupled to  
17      receive an input clock signal such as delayed clock signal  
18      D\_CLK (Figure 6). The output terminal of each delay line  
19      1010\_Z is coupled to the logic one input terminal of  
20      multiplexer 1030\_Z, where Z is an integer between 1 and 4,  
21      inclusive. The output terminal of each multiplexer 1030\_Z  
22      is coupled to the input terminal of delay line 1010\_Z+1,  
23      where Z is an integer between 1 and 3, inclusive. The  
24      output terminal of multiplexer 1030\_4 is coupled to an input  
25      terminal of phase detector 1020. The logic zero input  
26      terminals of multiplexer 1030\_1 and multiplexer 1030\_3 are  
27      coupled to ground. However, the logic zero input terminal  
28      of multiplexer 1030\_2 is coupled to the output terminal of  
29      delay line 1010\_1. Similarly, the logic zero input terminal  
30      of multiplexer 1030\_4 is coupled to the output terminal of  
31      delay line 1010\_3. Phase detector 1020 also receives input  
32      clock signal D\_CLK on another input terminal. Phase  
33      detector 1020 controls delay lines 1010\_1 to 1010\_4 in  
34      parallel as described above with respect to phase detector  
35      920.

1       If configuration line 1040 is pulled to logic one,  
2       which puts the embodiment of Figure 10 into the first mode,  
3       delay lines 1010\_1 to 1010\_4 are coupled in series. In the  
4       first mode, each delay line provides a delay of  $P/4$ . Thus,  
5       if the input clock signal is delayed clock signal D\_CLK, the  
6       output terminal of each multiplexer 1030\_2 can provide  
7       phase-shifted clock signals P\_CLK\_1, P\_CLK\_2, and P\_CLK\_3.

8       However, if configuration line 1040 is pulled to logic  
9       zero, which puts the embodiment of Figure 10 into the second  
10      mode, only delay line 1010\_1 and delay line 1010\_3 are  
11      coupled in series. Delay lines 1010\_2 and 1010\_4 have their  
12      input terminal coupled to ground through multiplexers 1030\_1  
13      and 1030\_3, respectively. In the second mode delay line  
14      1010\_1 and 1010\_3 each provide a delay of  $P/2$ . Coupling the  
15      input terminals of delay lines 1010\_2 and 1010\_4 to ground  
16      reduces power consumption and switching noise. However, in  
17      the second mode the embodiment of Figure 10 produces only  
18      one output clock signal, which is 180 degrees out of phase  
19      with the input clock signal and is generated at the output  
20      terminal of multiplexer 1030\_2.

21      Figure 11 shows one embodiment of output generator 640  
22      of Figure 6. The output generator of Figure 11 comprises an  
23      N-input multiplexer 1110. N-input multiplexer 1110 has N  
24      input terminals, referenced as 1110\_0 to 1110\_N-1, select  
25      terminals 1112, and an output terminal 1114. When the  
26      embodiment of output generator 640 of Figure 11 is used in  
27      delay lock loop 600 of Figure 6, select terminals 1112 are  
28      coupled to controller 630, input terminal 1110\_0 is coupled  
29      to receive delayed clock signal D\_CLK, output terminal 1114  
30      provides output clock signal O\_CLK, and input terminals  
31      1110\_1 to 1110\_N-1 are coupled to receive phase-shifted  
32      clock signals P\_CLK\_1 to P\_CLK\_N-1, respectively. Select  
33      signals on select terminals 1112 determine which input  
34      signal is provided on output terminal 1114. Other  
35      embodiments of output generator 640 may include additional  
36      circuitry, such as clock buffers and clock dividers. In

1 addition, some embodiments of output generator 640 drive  
2 additional clock signals, such as various versions of the  
3 phase-shifted clock signals.

4 Figure 12 shows a state diagram 1200 for one embodiment  
5 of controller 630 of Figure 6. On power-up or reset,  
6 controller 630 transitions to a reset stage 1210. In reset  
7 stage 1210, controller 630 sets a phase counter (not shown)  
8 to zero, which causes output generator 640 to provide  
9 delayed clock signal D\_CLK as output clock signal O\_CLK, and  
10 adjusts propagation delay D of delay line 610 (Figure 6) to  
11 a starting delay value. Starting delay values for  
12 propagation delay D include, for example, minimum  
13 propagation delay D\_MIN, maximum propagation delay D\_MAX, or  
14 the average of minimum propagation delay D\_MIN and maximum  
15 propagation delay D\_MAX. Controller 1210 then transitions  
16 to lock acquisition stage 1220.

17 In lock acquisition stage 1220, controller 630  
18 synchronizes reference clock signal REF\_CLK and skewed clock  
19 signal S\_CLK. Specifically, controller 630 adjusts  
20 propagation delay D of delay line 610 based on signals from  
21 phase detector 620. Phase detector 620 determines whether  
22 propagation delay D must be increased or decreased to  
23 synchronize skewed clock signal S\_CLK with reference clock  
24 signal REF\_CLK. Lock acquisition is described above in  
25 greater detail with respect to Figures 6-9; therefore, the  
26 description is not repeated. In some embodiments, clock  
27 phase shifter 650 is also reset by the power-on/reset  
28 signal. For some of these embodiments, controller 630 does  
29 not adjust propagation delay D until after clock phase  
30 shifter 650 produces phase-shifted clock signals P\_CLK\_1 to  
31 P\_CLK\_N-1. If controller 630 cannot synchronize skewed  
32 clock signal S\_CLK with reference clock signal REF\_CLK,  
33 controller 630 transitions to increment phase stage 1250,  
34 described below. Otherwise, controller 630 transitions to  
35 check lock window stage 1230 after controller 630  
36 synchronizes skewed clock signal S\_CLK with reference clock

1 signal REF\_CLK (with an initial propagation delay ID in  
2 delay line 610).

3 In check lock window stage 1230, controller 630 must  
4 determine whether initial propagation delay ID is within  
5 lock window W. Specifically, propagation delay ID is within  
6 lock window W if propagation delay ID is greater than lock  
7 window minimum W\_MIN and less than lock window maximum  
8 W\_MAX. If initial propagation delay ID is not within lock  
9 window W, controller 630 transitions to increment phase  
10 stage 1250. Otherwise, controller 630 transitions to lock  
11 maintenance stage 1240.

12 In lock maintenance stage 1240, controller 630 adjust  
13 propagation delay D of delay line 610 to maintain  
14 synchronization of skewed clock signal S\_CLK with reference  
15 clock signal REF\_CLK. Lock maintenance is described above  
16 in greater detail; therefore, the description is not  
17 repeated. As described above, the present invention can  
18 maintain lock throughout the systems environment conditions.  
19 Therefore, controller 630 remains in lock maintenance stage  
20 1240 unless a reset occurs that causes controller 630 to  
21 transition to reset stage 1210.

22 In increment phase stage 1250, controller 630  
23 increments the phase counter, which causes output generator  
24 640 to select a different phase-shifted clock signal.  
25 Further, controller 630 resets delay line 610 so that  
26 propagation delay D returns to the starting delay value used  
27 in reset stage 1210. Controller 630 then transitions to  
28 lock acquisition stage 1220 and proceeds as described above.

29 Figure 13 is a block diagram of another embodiment of  
30 delay lock loop 600. The embodiment of Figure 13 uses the  
31 same principles as described above with respect to the  
32 embodiment of Figure 6. However, in the embodiment of  
33 Figure 13, clock phase shifter 650 generates phase-shifted  
34 clock signals P\_CLK\_1 to P\_CLK\_N-1 using reference clock  
35 signal REF\_CLK. Reference clock signal REF\_CLK and phase-  
36 shifted clock signals P\_CLK\_1 to P\_CLK\_N-1 are coupled to an

1       input selector 1340. Input selector 1340 selects either  
2       reference clock signal REF\_CLK or one of phase-shifted clock  
3       signals P\_CLK\_1 to P\_CLK\_N-1 as a delay line input clock  
4       signal DLI\_CLK, which is provided to the input terminal of  
5       delay line 610. Delay line 610 drives output clock signal  
6       O\_CLK. A controller 1330 controls input selector 1340 and  
7       delay line 610 based on the phase information provided by  
8       phase detector 620 so that delay line 610 provides a  
9       propagation delay D that synchronizes skewed clock signal  
10      S\_CLK with reference clock signal REF\_CLK. Input selector  
11      1340 can be implemented using the same circuit design as  
12      output generator 640.

13      Fig. 14(a) is a block diagram of a digital frequency  
14      synthesizer 1400 in accordance with one embodiment of the  
15      present invention. Digital frequency synthesizer 1400  
16      generates a frequency adjusted clock signal FREQ\_CLK having  
17      a clock frequency  $F_{ADJ}$  equal to a clock frequency  $F_{SYNCH}$   
18      of a synchronizing clock signal SYNCH\_CLK multiplied by a  
19      multiplier M and divided by a divider D (i.e.,  
20       $F_{ADJ}=M*F_{SYNCH}/D$ ). As explained above, when digital  
21      frequency synthesizer 320 is used with digital clock manager  
22      300, 400, or 500, clock frequency  $F_{SYNCH}$  of synchronizing  
23      clock signal SYNCH\_CLK is equal to clock frequency  $F_{REF}$  of  
24      reference clock signal REF\_CLK. Digital frequency  
25      synthesizer 1400 comprises clock dividers 1410 and 1420,  
26      optional clock selector 1430, phase comparator 1440,  
27      halt/restart circuit 1445, initialization circuit 1450,  
28      oscillator control circuit 1460, and variable digital  
29      oscillator 1470. Clock divider 1410 receives frequency  
30      adjusted clock signal FREQ\_CLK, which is generated by  
31      variable digital oscillator 1470, and generates feedback  
32      clock signal FBK\_CLK having a frequency  $F_{FBK}$  equal to  
33      frequency  $F_{ADJ}$  of output clock FREQ\_CLK divided by  
34      multiplier M. Clock divider 1410 drives feedback clock  
35      signal FBK\_CLK to initialization circuit 1450 and phase  
36      comparator 1440. Clock divider 1420 receives synchronizing

1       clock signal SYNCH\_CLK and generates divided synchronizing  
2       clock signal D\_SYNCH\_CLK having a frequency F\_D\_SYNCH equal  
3       to frequency F\_SYNCH of synchronizing clock signal SYNCH\_CLK  
4       divided by divider D. Clock divider 1420 drives divided  
5       synchronizing clock signal D\_SYNCH\_CLK to initialization  
6       circuit 1450 and phase comparator 1440.

7       Clock selector 1430 receives both synchronizing clock  
8       signal SYNCH\_CLK and frequency adjusted clock signal  
9       FREQ\_CLK and selectively drives either synchronizing clock  
10      signal SYNCH\_CLK or frequency adjusted clock signal FREQ\_CLK  
11      as control clock signal CTRL\_CLK to initialization circuit  
12      1450 and oscillator control circuit 1460. Generally,  
13      synchronizing clock signal SYNCH\_CLK is used during a coarse  
14      frequency search phase. Then, frequency adjusted clock  
15      signal FREQ\_CLK is used for a fine frequency search phase as  
16      well as during a clock maintenance phase, i.e., maintaining  
17      the frequency of frequency adjusted clock signal FREQ\_CLK at  
18      the selected frequency. The coarse frequency search phase,  
19      the fine frequency search phase, and the maintenance phase  
20      for one embodiment of the present invention is described in  
21      detail below. Halt/restart circuit 1445, which is used  
22      during coarse frequency search phase and the fine frequency  
23      search phase, is described below.

24      At power-on or reset, initialization circuit 1450  
25      controls oscillator control circuit 1460 to tune variable  
26      digital oscillator 1470 to generate frequency adjusted clock  
27      signal FREQ\_CLK. Specifically, initialization circuit 1450  
28      tunes variable digital oscillator 1470 so that frequency  
29      F\_ADJ of frequency adjusted clock signal FREQ\_CLK is equal  
30      to a selected frequency F\_SEL, which equals frequency  
31      F\_SYNCH of synchronizing clock signal SYNCH\_CLK multiplied  
32      by multiplier M and divided by divider D. After frequency  
33      F\_ADJ of frequency adjusted clock signal FREQ\_CLK reaches  
34      selected clock frequency F\_SEL, initialization circuit 1450  
35      passes control of oscillator control circuit 1460 and  
36      variable digital oscillator 1470 to phase comparator 1440.

1 Phase comparator 1440 tunes variable digital oscillator 1470  
2 to maintain frequency  $F_{ADJ}$  at selected frequency  $F_{SEL}$   
3 despite environmental changes such as temperature.

4 Some embodiments of digital frequency synthesizer 1400  
5 can use conventional clock dividers, clock selectors,  
6 halt/restart circuits, and phase comparators. However,  
7 detailed descriptions of specific embodiments of  
8 initialization circuits 1450, oscillator control circuit  
9 1460, and variable digital oscillator 1470 are described  
10 below.

11 Fig. 14(b) is a timing diagram for digital frequency  
12 synthesizer 1400. For clarity, Fig 14(b) is idealized and  
13 omit such factors as propagation delay and skewing. In Fig.  
14 14(b), multiplier M is equal to 7 and divider D is equal to  
15 5. Thus, as shown in Fig. 14(b), divided synchronizing  
16 clock signal D\_SYNCH\_CLK has a rising edge, such as rising  
17 edges 1421, 1423, and 1425, at every fifth rising edge of  
18 synchronizing clock signal SYNCH\_CLK, i.e., at rising edges  
19 1401, 1403, and 1405. Similarly, feedback clock signal  
20 FBK\_CLK has a rising edge, such as rising edges 1411, 1413,  
21 and 1415, every seventh rising edge of frequency adjusted  
22 clock signal FREQ\_CLK, i.e., at rising edges 1471, 1473 and  
23 1475. When frequency  $F_{ADJ}$  of frequency adjusted clock  
24 signal FREQ\_CLK is equal to selected frequency  $F_{SEL}$  and  
25 synchronizing clock signal SYNCH\_CLK is in phase with  
26 frequency adjusted clock signal FREQ\_CLK, feedback clock  
27 signal FBK\_CLK and divided synchronizing clock signal  
28 D\_SYNCH\_CLK have the same phase and frequency. Accordingly,  
29 initialization circuit 1450 and phase comparator 1440 tune  
30 variable digital oscillator 1470 to match the phase and  
31 frequency of divided synchronizing clock signal D\_SYNCH\_CLK  
32 and feedback clock signal FBK\_CLK to drive frequency  
33 adjusted clock signal FREQ\_CLK at selected frequency  $F_{SEL}$ .  
34 When the phase and frequency of divided synchronizing clock  
35 signal D\_SYNCH\_CLK and feedback clock signal FBK\_CLK match,  
36 every Mth rising edge of frequency adjusted clock signal

1 FREQ\_CLK aligns with a rising edge of synchronizing clock  
2 signal SYNCH\_CLK. For example, rising edges 1471 and 1473  
3 of frequency adjusted clock signal FREQ\_CLK align with  
4 rising edges 1401 and 1403 of synchronizing clock signal  
5 SYNCH\_CLK. The alignments are commonly referred to as  
6 concurrences. The time between two consecutive concurrences  
7 is commonly referred to as a concurrence period.

8 Fig. 15 is a block diagram of an embodiment of variable  
9 digital oscillator 1470. The embodiment of Fig.3 comprises  
10 a dual-input edge-triggered SR circuit 1510, an inverter  
11 1540, and a variable delay line 1520 having a low precision  
12 delay line 1525 and a trim circuit 1527. Dual-input edge-  
13 triggered SR circuit 1510 includes a first set input  
14 terminal S\_IN1, a first set enable input terminal S\_EN1, a  
15 second set input terminal S\_IN2, a second set enable input  
16 S\_EN2, a first reset input terminal R\_IN1, a first reset  
17 enable input terminal R\_EN1, a second reset input terminal  
18 R\_IN2, a second reset enable input terminal R\_EN2, and an  
19 output terminal OUT. Operation and construction of dual-  
20 input edge-triggered SR circuits are well known in the art  
21 and therefore are not described in detail herein. Table 1  
22 provides a truth table for an active high version of dual-  
23 input edge-triggered SR CIRCUIT 1510. Basically, an active  
24 (e.g., rising) edge of a set input signal on a set terminal  
25 while the corresponding set enable signal at the set enable  
26 terminal is at an enabled logic level (e.g., logic high)  
27 causes output terminal OUT to drive an output signal to an  
28 active state (e.g., logic high). Conversely, an active  
29 (e.g., rising) edge on a reset input signal on a reset  
30 terminal while the corresponding reset enable signal on the  
31 corresponding reset enable terminal is at an enabled logic  
32 level (e.g., logic high) causes output terminal OUT to drive  
33 an output signal to an inactive state (e.g., logic low).  
34 For clarity, the circuits herein are described using logic  
35 high as the enabled logic level and the active logic level.  
36 Similarly, rising edges are used as the active edges.

1 However, those skilled in the art can apply the principles  
2 of the present invention using different enabled logic  
3 levels, active logic levels, and active edges.  
4

5 TABLE 1  
6

S_IN1	S_EN1	S_IN2	S_EN2	R_IN1	R_EN1	OUT
RE	H	X	X	X	X	H
X	X	RE	H	X	X	H
X	X	X	X	RE	H	L

11 where RE is a rising edge, H is logic high, L is logic low,  
12 and X is a do not care condition.  
13

14 Synchronizing clock signal SYNCH\_CLK is coupled to  
15 first set input terminal S\_IN1 and a reference clock enable  
16 signal R\_CLK\_EN is coupled to first enable input terminal  
17 S\_EN1. Output terminal OUT of dual edge-triggered SR  
18 CIRCUIT 1510 drives frequency adjusted clock signal FREQ\_CLK  
19 and is coupled to variable delay line 1520. In the  
20 embodiment of Fig. 15, variable delay line 1520 is  
21 implemented using a low precision delay line 1525 have a  
22 base delay BD and a trim circuit 1527 that provides a delay  
23 of 0, 0.25, 0.50, or 0.75 times base delay BD. Other  
24 embodiments of the present invention can use conventional  
25 variable delay lines. Variable delay line 1520 delays the  
26 output signal of dual-input edge-triggered SR circuit 1510  
27 by a variable amount under the control of oscillator control  
28 circuit 1460 to generate delayed output signal D\_OUT.  
29 Delayed output signal D\_OUT is coupled to first reset input  
30 signal R\_IN1 as well as the input terminal of inverter 1540.  
31 The output terminal of inverter 1540 is coupled to second  
32 set input terminal S\_IN2. An oscillator enable signal  
33 OSC\_EN is coupled to second set enable terminal S\_EN2.  
34 Under normal operations, oscillator enable signal OSC\_EN is  
35 in the logic high state to enable variable digital  
36 oscillator 1470. Therefore, a rising edge from output  
37 terminal OUT that is delayed by variable delay line 1520  
38 causes dual-input edge-triggered SR circuit 1510 to  
39 transition to logic low. Conversely, a falling edge from

1 output terminal OUT that is delayed by variable delay line  
2 1520 and inverted by inverter 1540 causes dual-input edge-  
3 triggered SR circuit 1510 to transition to logic high.  
4 Thus, variable digital oscillator 1470 generates a clock  
5 signal such as frequency adjusted clock signal FREQ\_CLK.  
6 The frequency of frequency adjusted clock signal FREQ\_CLK is  
7 controlled by the amount of delay provided by variable delay  
8 line 1520.

9 In the embodiment of Fig. 15, low precision variable  
10 delay line 1525 provides a variable delay ranging from 0 to  
11 127 times low precision base delay LBD, where low precision  
12 base delay LBD is the smallest non-zero delay provided by  
13 low precision variable delay 1525. Furthermore, trim  
14 circuit 1530 provides an additional delay of 0, 0.25, 0.5 or  
15 0.75 base delay units. Thus, in the embodiment of Fig. 15,  
16 variable delay line 1520 can provide 512 delay values  
17 ranging from 0 to 127.75 low precision base delay LBD in  
18 multiples of 0.25 low precision base delay LBD. Thus, in  
19 the embodiment of Fig. 15, variable delay line 1520 provides  
20 a delay between 0 and 511 times a base delay BD, which is  
21 equal to 0.25 times low precision base delay LBD.

22 Depending on the frequency  $F_{SYNCH}$  of synchronizing  
23 clock signal SYNCH\_CLK, multiplier M, and divisor D,  
24 variable delay line 1520 may not be able to provide the  
25 exact amount of delay necessary to generate frequency  
26 adjusted clock signal FREQ\_CLK at selected frequency  $F_{SEL}$ .  
27 Fig. 16 illustrates this problem of using digital delay  
28 lines in clock generation circuits. Specifically, Fig. 16  
29 shows a synchronizing clock signal SYNCH\_CLK, a conventional  
30 frequency adjusted clock signal C\_FREQ\_CLK, and an frequency  
31 adjusted clock signal FREQ\_CLK generated using a dual-input  
32 edge-triggered SR circuit 1510 in accordance with one  
33 embodiment of the present invention. In Fig. 16, rising  
34 edges 1651, 1661, and 1671 of synchronizing clock signal  
35 SYNCH\_CLK, conventional frequency adjusted clock signal

1 C\_FREQ\_CLK, and frequency adjusted clock signal FREQ\_CLK,  
2 respectively, are synchronized.

3 In Fig. 16, multiplier M is equal to 4 and divider D is  
4 equal to 1. Synchronizing clock signal SYNCH\_CLK has a  
5 period of 50 nanoseconds. Accordingly, 25 nanoseconds  
6 separates each consecutive clock edge in synchronizing clock  
7 signal SYNCH\_CLK. Ideally, variable delay line 1520 would  
8 provide a delay of 6.25 nanoseconds, which is equal to 25  
9 divided by 4. However, if the base delay unit of variable  
10 delay line 1520 (Fig. 15) is one nanosecond, then variable  
11 delay line 1520 is configured to provide 6 nanoseconds of  
12 delay between consecutive edges of frequency adjusted clock  
13 signal FREQ\_CLK1. As explained above, during concurrence,  
14 i.e., every 4 periods, the rising edge of conventional  
15 frequency adjusted clock signal C\_FREQ\_CLK should occur at  
16 the same time as the rising edge of synchronizing clock  
17 signal SYNCH\_CLK. However, as illustrated in Fig. 16,  
18 rising edge 1665 of conventional output clock C\_FREQ\_CLK  
19 precedes rising edge 1655 of synchronizing clock signal  
20 SYNCH\_CLK by 2 nanoseconds. The two nanosecond misalignment  
21 reoccurs every concurrence period. Thus, over time the  
22 misalignment can cause serious synchronization problems in  
23 digital systems.

24 To eliminate the misalignment, just prior to  
25 concurrence, i.e., when a rising edge of synchronizing clock  
26 signal SYNCH\_CLK should be aligned with a rising edge of  
27 frequency adjusted clock signal FREQ\_CLK, oscillator enable  
28 signal OSC\_EN is deasserted and reference clock enable  
29 signal is asserted. Thus, during a concurrence the rising  
30 edge of synchronizing clock signal SYNCH\_CLK on input  
31 terminal S\_IN1 of dual-input edge-triggered SR circuit 1510  
32 causes a rising edge on output terminal OUT of dual-input  
33 edge-triggered SR circuit 1510, which drives frequency  
34 adjusted clock signal FREQ\_CLK. After concurrence,  
35 oscillator enable signal OSC\_EN is reasserted and reference  
36 clock enable signal R\_CLK\_EN is deasserted. Thus, every Mth

1       clock period of frequency adjusted clock signal FREQ\_CLK,  
2       frequency adjusted clock signal FREQ\_CLK is realigned with  
3       synchronizing clock signal SYNCH\_CLK even if variable delay  
4       line 1520 does not provide the exact delay necessary to  
5       drive frequency adjusted clock signal FREQ\_CLK at selected  
6       frequency F\_SEL.

7       Accordingly, as shown in Fig. 16, rising edge 1675 of  
8       frequency adjusted clock signal FREQ\_CLK is aligned with  
9       rising edge 1655 of synchronizing clock signal SYNCH\_CLK.  
10      Therefore, the time between falling edge 1671 of frequency  
11      adjusted clock signal FREQ\_CLK and rising edge 1675 of  
12      frequency adjusted clock signal FREQ\_CLK is 8 nanoseconds  
13      rather than 6 nanoseconds. Thus, the time period during a  
14      concurrence cycle of frequency adjusted clock signal  
15      FREQ\_CLK is equal to 50 nanoseconds rather than 48  
16      nanoseconds as would be dictated by using only variable  
17      delay line 1520 to control the clock edges of frequency  
18      adjusted clock signal FREQ\_CLK. Consequently, the average  
19      frequency of frequency adjusted clock signal FREQ\_CLK over  
20      an concurrence period is equal to selected frequency F\_SEL.

21      Fig. 17 is a block diagram of oscillator control  
22      circuit 1460 in accordance with one embodiment of the  
23      present invention. The embodiment of Fig. 17 includes a  
24      delay line register 1710, an optional incrementer 1730, an  
25      optional delay line fine tuning controller 1720, and an  
26      optional OR gate 1740. Delay line register 1710 receives a  
27      delay value DV[8:0] from initialization circuit 1450 (Fig.  
28      14). The contents of delay line register 1710 are provided  
29      to incrementer 1730 and initialization circuit 1450 as delay  
30      value feedback signals DV\_FB[8:0]. Initialization circuit  
31      1450 adjusts delay value DV[8:0] during the coarse frequency  
32      search phase to match frequency F\_ADJ of frequency adjusted  
33      clock signal FREQ\_CLK with selected frequency F\_SEL as  
34      described below. Delay line register 1710 also receives a  
35      carry signal CARRY and a borrow signal BORROW from delay  
36      line fine tuning controller 1720. IF delay line fine tuning

1 controller 1720 is enabled, delay line register 1710 is  
2 configured to increment when carry signal CARRY is in the  
3 active logic level (e.g., logic high) and to decrement on  
4 when borrow signal BORROW is in the active logic level  
5 (e.g., logic high). Generation of carry signal CARRY and  
6 borrow signal BORROW is described below.

7 The delay value in delay line register 1710 is  
8 selectively incremented by incrementer 1730 to generate  
9 delay select signals  $DELAY\_SEL[8:0]$ , which are coupled to  
10 variable delay line 1520 (Fig. 15). Specifically, delay  
11 line fine tuning controller 1720 drives a fine tuning  
12 increment control signal  $FT\_INC$  to incrementer 1730. If  
13 fine tuning increment control signal  $FT\_INC$  is at an active  
14 logic level (e.g., logic high), then incrementer 1730  
15 increments the value from delay line register 1710. Delay  
16 line fine tuning controller 1720 is controlled by frequency  
17 comparator 1450 using control signal  $A/!S$  or by phase  
18 comparator 1440 (Fig. 14(a)) using phase comparator control  
19 signal  $PC\_CTRL$ . For the embodiment of Fig. 17, if delay  
20 line fine tuning controller 1720 is enabled then if either  
21 control signal  $A/!S$  or phase comparator signal  $PC\_CTRL$  is in  
22 the active state (i.e., logic high) then delay line fine  
23 tuning controller 1720 is configured to add additional delay  
24 during a concurrence period. Thus, OR gate 1740 generates  
25 add delay signal  $ADD\_DELAY$  from control signal  $A/!S$  and  
26 phase comparator control signal  $PC\_CTRL$ . The use of delay  
27 line fine tuning controller 1720 is described in detail  
28 below.

29 Fig. 18 is a block diagram of initialization circuit  
30 1450 in accordance with one embodiment of the present  
31 invention. Initialization circuit 1450 performs a coarse  
32 frequency search to set the value in variable delay line  
33 1520. Specifically, during the coarse frequency search  
34 phase, the embodiment of Fig. 18 performs a fast binary  
35 search to determine delay value  $DV[8:0]$  for delay line  
36 register 1710, which causes frequency  $F\_FBK$  of feedback

1       clock FBK\_CLK and frequency F\_D\_SYNCH of divided reference  
2       clock D\_SYNCH\_CLK to be equal. Other embodiments of  
3       initialization circuit 1450 may use other methods to select  
4       delay value DV[8:0] for delay line register 1710. The  
5       embodiment of Fig. 18 comprises a right shift register 1830,  
6       an adder/subtractor 1840, a frequency comparator 1850, and  
7       an overflow register 1860.

8       Initially, adder/subtractor 1840 is configured to  
9       provide a delay value DV[8:0] that causes variable delay  
10      line 1520 to provide 50% of the maximum delay that can be  
11      provided by variable delay line 1520. For the embodiment of  
12      Fig. 15, delay value DV[8:0] is initially set at 256, i.e.,  
13      halfway between 0 and 511. Right shift register 1830 is  
14      initially configured to be equal to half of the initial  
15      value of delay value DV[8:0]. Thus, for the embodiment of  
16      Fig. 15, right shifter 1830 is configured with an initial  
17      value of 128. Adder/subtractor 1840 is controlled by  
18      frequency comparator 1850 to either add the value in right  
19      shifter 1830 to the value in delay line register 1710 (Fig.  
20      17) or to subtract the value in right shifter 1830 to the  
21      value in delay line register 1710. Specifically, the value  
22      in delay line register 1710 is provided by delay value  
23      feedback signals DV\_FB[8:0]. After each addition or  
24      subtraction operation, the content of right shifter 1830 is  
25      "right shifted", which effectively divides the value in  
26      right shifter 1830 in half. However, right shifter 1830  
27      maintains a minimum value of 1.

28      Frequency comparator 1850 receives feedback clock  
29      signal FBK\_CLK and divided reference signal D\_SYNCH\_CLK and  
30      generates a control signal A/S which dictates whether  
31      adder/subtractor 1840 performs an ADD operation or a  
32      SUBTRACT operation. Specifically, if frequency F\_FBK of  
33      feedback clock signal FBK\_CLK is greater than frequency  
34      F\_D\_SYNCH of divided synchronizing clock signal D\_SYNCH\_CLK,  
35      the delay provided by variable delay line should be  
36      increased. Accordingly, frequency comparator 1850 causes

1 adder/subtractor 1840 to perform an ADD operation by driving  
2 control signal A/!S to the add logic level (typically logic  
3 high). Conversely, if frequency F\_FBK of feedback clock  
4 signal FBK\_CLK is less than frequency F\_D\_SYNCH of divided  
5 synchronizing clock signal D\_SYNCH\_CLK, the delay provided  
6 by variable delay line should be decreased. Accordingly,  
7 frequency comparator 1850 causes adder/subtractor 1840 to  
8 perform a SUBTRACT operation by driving control signal A/!S  
9 to the subtract logic level (typically logic low). After  
10 each addition or subtraction, halt/restart circuit 1445  
11 (Fig. 14) halts and restarts initialization circuit 1450,  
12 and oscillator control circuit 1460 so that frequency  
13 adjusted clock signal FREQ\_CLK is started in phase with  
14 synchronizing clock signal SYNCH\_CLK. Halting and  
15 restarting allows frequency comparator 1850 to determine the  
16 proper value of control signal A/!S without having to  
17 compensate for phase variations. However, some embodiments  
18 of the present invention may use frequency comparators that  
19 automatically compensate for phase variations. For these  
20 embodiments, halting and restarting may not be necessary.

21 In some embodiments of the present invention, frequency  
22 comparator 1850 also generates a frequency comparator  
23 reversal signal FC\_REV. Frequency comparator reversal  
24 signal FC\_REV is driven to a active state (e.g., logic high)  
25 when frequency F\_FBK of feedback clock signal FBK\_CLK  
26 becomes greater than frequency F\_D\_SYNCH of divided  
27 synchronizing clock signal D\_SYNCH\_CLK and also when  
28 frequency F\_D\_SYNCH of divided synchronizing clock signal  
29 D\_SYNCH\_CLK becomes greater than frequency F\_FBK of feedback  
30 clock signal FBK\_CLK. In one embodiment of the present  
31 invention, a coarse frequency search phase ends when the  
32 value of right shifter 1830 is equal to one.

33 Table 2 provides an example of the operation for the  
34 embodiment of initialization circuit 1450 in Fig. 18. In  
35 the example of Table 2, a delay value DV of 371.5 provides  
36 the optimum delay for matching frequency F\_FBK of feedback

1      clock signal FBK\_CLK to frequency F\_D\_SYNCH of divided  
 2      synchronizing clock signal D\_SYNCH\_CLK.

4                    TABLE 2  
 5

6      Coarse	7      Frequency	8      Right Shifter	9      Delay Line	10     Register 1730	11     A/S
12     Search Step	13 <u>1830</u>	14	15	16	17
18	0	128	256	1	
19	1	64	384	0	
20	2	32	320	1	
21	3	16	352	1	
22	4	8	368	1	
23	5	4	376	0	
24	6	2	372	0	
25	7	1	370	1	
26	8	1	371	1	
27	9	1	372	0	
28	10	1	371	1	

29     As explained above initially delay line register 1710 is  
 30     configured to contain 256 and right shift register 1830 is  
 31     configured to contain 128. Because the ideal value for  
 32     delay value DV is 371.5, control signal A/S is in the Add  
 33     state (i.e., logic high). At step 1, adder/subtractor 1840  
 34     adds 128 to 256; delay line register 1710 stores 384 (i.e.,  
 35     256+128); and right shifter 1830 right shifts 128, which  
 36     becomes 64. When delay line register 1710 contains 384  
 37     frequency comparator 1850 drives control line A/S to the  
 38     subtract logic level (i.e., logic low). Then, in step 2,  
 39     adder/subtractor 1840 subtracts 64 from 384; delay line  
 40     register 1710 stores 320 (i.e., 384-64); and right shifter  
 41     1830 right shifts 64 which becomes 32. When delay line  
 42     register 1710 contains 320 frequency comparator 1850 drives  
 43     control line A/S to the add logic level (i.e., logic high).  
 44     This process continues until the value in delay line  
 45     register 1710 is as close to the optimum value as possible.

46     Overflow register 1860 receives output bit 9 of  
 47     adder/subtractor 1840. If output bit 9 is active, an  
 48     overflow conditions has occurred and must be remedied by an  
 49     outside control system (not shown). Typically, overflow

1 conditions only occur if clock divider/multiplier 1400 is  
2 used with clock frequencies that are too fast or too slow  
3 compared to the possible delay time provided by variable  
4 delay line 1520.

5 As stated above, some embodiments of the present  
6 invention perform a fine frequency search using delay line  
7 fine tuning controller 1720 after initialization circuit  
8 1450 establishes a delay value DV[8:0]. As explained above,  
9 variable digital delay lines may not be able to provide the  
10 exact delay necessary to generate frequency adjusted clock  
11 signal FREQ\_CLK at selected frequency F\_SEL. The present  
12 invention solves this problem by using dual-input edge-  
13 triggered SR circuit 1510 (Fig. 15) to synchronize rising  
14 clock edges on frequency adjusted clock signal FREQ\_CLK to  
15 reference clock SYNCH\_CLK during a concurrence of frequency  
16 adjusted clock signal FREQ\_CLK and synchronizing clock  
17 signal SYNCH\_CLK. As explained above, a concurrence occurs  
18 when a rising edge of frequency adjusted clock signal  
19 FREQ\_CLK is suppose to be aligned with a rising edge  
20 synchronizing clock signal SYNCH\_CLK, i.e., every Mth rising  
21 edge. However, between concurrence the frequency and phase  
22 of frequency adjusted clock signal FREQ\_CLK may differ from  
23 an ideal clock signal at selected frequency F\_SEL. Delay  
24 line fine tuning controller 1720 selectively adjusts the  
25 delay provided by variable delay line 1520 to better match  
26 the frequency and phase of the ideal frequency adjusted  
27 clock signal.

28 Effectively, delay line fine tuning controller 1720  
29 adds additional precision to variable delay line 1520 by  
30 selectively increasing the delay provided by variable delay  
31 line 1520 by one base delay BD at various times during a  
32 concurrence period. Fig. 19 illustrates the advantages  
33 provided by delay line fine tuning controller 1720.  
34 Specifically, Fig. 19 shows a synchronizing clock signal  
35 SYNCH\_CLK, an ideal frequency adjusted clock signal  
36 I\_FREQ\_CLK, an frequency adjusted clock signal FREQ\_CLK1

1 using a dual-input edge-triggered SR circuit in accordance  
2 with one embodiment of the present invention, and an  
3 frequency adjusted clock signal FREQ\_CLK2 using both a dual-  
4 input edge-triggered SR circuit and delay line fine tuning  
5 controller 1720 in accordance with another embodiment of the  
6 present invention.

7 In Fig. 19, multiplier M is equal to 4 and divider D is  
8 equal to 1. Synchronizing clock signal SYNCH\_CLK has a  
9 period of 50 nanoseconds. Accordingly, 25 nanoseconds  
10 separates each consecutive clock edge in synchronizing clock  
11 signal SYNCH\_CLK. Ideal frequency adjusted clock signal  
12 I\_FREQ\_CLK has a period of 12.5 nanoseconds. Accordingly,  
13 6.25 nanoseconds separates each consecutive clock edge in  
14 ideal frequency adjusted clock signal I\_FREQ\_CLK. If the  
15 base delay unit of variable delay line 1520 (Fig. 15) is one  
16 nanosecond, then variable delay line 1520 is configured to  
17 provide 6 nanoseconds of delay between consecutive edges of  
18 frequency adjusted clock signal FREQ\_CLK1. However, during  
19 a concurrence, the rising edge of frequency adjusted clock  
20 signal FREQ\_CLK1 is controlled by the rising edge of  
21 synchronizing clock signal SYNCH\_CLK. Accordingly, rising  
22 edge 1935 of frequency adjusted clock signal FREQ\_CLK1 is  
23 aligned with rising edge 1915 of synchronizing clock signal  
24 SYNCH\_CLK. Therefore, the time between falling edge 1934 of  
25 frequency adjusted clock signal FREQ\_CLK1 and rising edge  
26 1935 of frequency adjusted clock signal FREQ\_CLK1 is 8  
27 nanoseconds. Thus, the average period during a concurrence  
28 cycle of frequency adjusted clock signal FREQ\_CLK1 is equal  
29 to 12.5 nanoseconds. However, frequency adjusted clock  
30 signal FREQ\_CLK1 is distorted from ideal frequency adjusted  
31 clock signal I\_FREQ\_CLK because the required extra delay  
32 during a concurrence period is bunched at the end of the  
33 concurrence period.

34 Delay line fine tuning controller 1720 selectively  
35 increments the delay provided by delay line 1520 to more  
36 closely match ideal frequency adjusted clock signal

1       I\_FREQ\_CLK. Rather than lumping the extra delay required to  
2       match the average period of frequency adjusted clock signal  
3       FREQ\_CLK2 with ideal frequency adjusted clock signal  
4       I\_FREQ\_CLK at the of the concurrence period, delay line fine  
5       tuning controller 1720 spreads the additional required base  
6       delay units over the entire concurrence period. Thus,  
7       falling clock edge 1942 and rising clock edge 1943 of  
8       frequency adjusted clock signal FREQ\_CLK2 are separated by 7  
9       nanoseconds rather than 6 nanoseconds. Similarly, falling  
10      clock edge 2046 and rising clock edge 1947 of frequency  
11      adjusted clock signal FREQ\_CLK2 are separated by 7  
12      nanoseconds rather than 6 nanoseconds. Thus, the waveform  
13      of frequency adjusted clock signal FREQ\_CLK2 more closely  
14      matches ideal frequency adjusted clock signal I\_FREQ\_CLK  
15      than frequency adjusted clock signal FREQ\_CLK1.

16      Fig. 20 is a block diagram of a delay line fine tuning  
17      controller 1720 in accordance with one embodiment of the  
18      present invention. The embodiment of Fig. 20 includes an  
19      up/down counter 2020, a modulo-M delta sigma circuit 2030,  
20      AND gate 2040, an AND gate 2050, and an inverter 2060.  
21      Up/down counter 2020 is configured to count in modulo M.  
22      For example, if M is equal to 4, up/down counter 2020 would  
23      count up in the sequence 0, 1, 2, 3, 0, 1, etc. and count  
24      down in the sequence 3, 2, 1, 0, 3, 2, etc.

25      Conceptually, up/down counter 2020 is used to provide  
26      high precision bits for delay line register 1710.  
27      Specifically, the value in up/down counter 2020 indicates  
28      the number of additional base delay units needed during a  
29      concurrence period to more precisely match frequency F\_ADJ  
30      of frequency adjusted clock signal FREQ\_CLK to selected  
31      frequency F\_SEL. In the example of Fig. 19, the base delay  
32      value is 1 nanoseconds,  
33      the delay value in delay line register 1710 is equal to 6  
34      (i.e., one period of frequency adjusted clock signal  
35      FREQ\_CLK is 12 nanoseconds), the period of concurrence is 50  
36      nanoseconds, and M is equal to 4. Thus, M periods of

1 frequency adjusted clock signal FREQ\_CLK is equal to 48  
2 nanoseconds (i.e.,  $4 * 12$  nanoseconds). However, since the  
3 concurrence period is 50 nanoseconds, two more base delay  
4 units should be added to frequency adjusted clock signal  
5 FREQ\_CLK during each concurrence period. Therefore, up/down  
6 counter 2020 should contain the value 2. Thus, in general  
7 up/down counter 2020 should be equal to the concurrence  
8 period minus M times two times the base delay value.  
9 However, during actual operation the information to  
10 calculate the value for up/down counter 2020 is not  
11 generally available. Therefore, searching techniques are  
12 used to calculate the value for up/down counter 2020. A  
13 searching technique in accordance with one embodiment of the  
14 present invention is described below.

15 Up/down counter 2020 receives the value M-1 (i.e.,  
16 multiplier M minus 1) on input terminals IN[7:0] via signals  
17 M\_m1[7:0]. Up/down counter 2020 provides both an output  
18 value OUT[7:0] and a next value NEXT[7:0]. Output value  
19 OUT[7:0] transitions on rising clock edges of control clock  
20 CTRL\_CLK. In contrast, next value NEXT[7:0] is equal to  
21 the value that OUT[7:0] will become after the next rising  
22 clock edge. Add delay signal ADD\_DELAY is also provided to  
23 control terminal UP. If add delay signal ADD\_DELAY is  
24 driven to the active logic level (i.e., logic high) up/down  
25 counter 2020 counts up. Otherwise, up down/counter 2020  
26 counts down.

27 To force modulo M counting, up/down counter 2020  
28 includes a synchronous reset terminal coupled to the output  
29 terminal of AND gate 2040. AND gate 2040, which receives  
30 status signal OUT=M\_m1 and add delay control signal  
31 ADD\_DELAY, generates carry signal CARRY. Status signal  
32 OUT=M\_m1 is driven to logic high when output value OUT[7:0]  
33 is equal to multiplier M minus 1. Status signal OUT=M\_m1 is  
34 typically generated by a comparator (not shown). Thus, if  
35 up/down counter 2020 is counting up and output value  
36 OUT[7:0] is equal to multiplier M minus 1, then up/down

1 counter 2020 is reset to zero on the next rising edge of  
2 clock signal CTRL\_CLK. Carry signal CARRY is also provided  
3 to delay line register 1710. An active logic level (e.g.,  
4 logic high) on carry signal CARRY enables delay line  
5 register 1710 to increment.

6 Up/down counter 2020 also includes a load control  
7 terminal LOAD coupled to the output terminal of AND gate  
8 2050. AND gate 2050, which receives status signal OUT=ZERO  
9 and add delay control signal ADD\_DELAY through inverter  
10 2060, generates borrow signal BORROW. Status signal  
11 OUT=ZERO is driven to logic high when output value OUT[7:0]  
12 is equal to zero. Status signal OUT=ZERO is typically  
13 generated by a comparator (not shown). Thus, if up/down  
14 counter 2020 is counting down and output value OUT[7:0] is  
15 equal to zero, then up/down counter 2020 is configured to  
16 load M minus 1. Borrow signal BORROW is also provided to  
17 delay line register 1710. An active logic level (e.g.,  
18 logic high) on Borrow signal BORROW enables delay line  
19 register 1710 to decrement.

20 Next signal NEXT[7:0] is coupled to pulse input  
21 terminals P\_IN[7:0] of modulo-M delta-sigma circuit 2030.  
22 Modulo-M delta sigma circuit 2030 also receives value M-1  
23 (i.e., multiplier M minus 1) on modulo input terminals  
24 M\_IN[7:0] via signals M\_m1[7:0], a pre-concurrence signal  
25 PRE\_CONC, and control clock signal CTRL\_CLK. Modulo-M  
26 delta-sigma circuit 2030, drives fine tuning increment  
27 control signal FT\_INC. For clarity, modulo-M delta sigma  
28 circuit 2030 is said to receive a modulo value M (although  
29 in the embodiment of Fig. 20, M minus 1 is actually  
30 received) and a pulse count P. Pre-concurrence signal  
31 PRE\_CONC, which is provided to reset terminal RESET of  
32 modulo-M delta sigma circuit 2030, is driven to the active  
33 logic level (e.g., logic high) the clock cycle prior to a  
34 concurrence. During M periods fine tuning increment  
35 control signal FT\_INC should contain P active pulses. The  
36 active pulses on fine tuning increment control signal FT\_INC

1 should be spread out across the M Periods. Table 3 provides  
2 some samples of fine tuning increment control signal FT\_INC,  
3 where a "1" represents an active pulse and "0" represents an  
4 inactive pulse.

5 TABLE 3  
6  
7  
8

9

M	P	FT_INC
--	--	-----
11 4	2	1010
12 6	2	100100
13 6	3	101010
14 6	5	111110
15 7	3	1010100
16 7	4	1101010
17 9	4	101010100
18 12	5	101010010100
19 15	3	100001000010000

20  
21 Concurrence  
22

23 Fig. 21 is a block diagram of modulo-M delta sigma  
24 circuit 2030 in accordance with one embodiment of the  
25 present invention. The embodiment of Fig. 21 includes an  
26 incrementer 2105, a multiplier 2110, a subtracter 2120, an  
27 adder 2130, a multiplexing circuit 2140, a latch 2150, and a  
28 comparator 2160. Modulo input terminals M\_IN[7:0] are  
29 coupled to an input port IN of incrementer 2105, a second  
30 input port IN2 of multiplexing circuit 2140, and a second  
31 input port IN2 of comparator 2160. Because the specific  
32 embodiment of Fig. 21 is designed to receive modulo value M  
33 minus 1 rather than modulo value M on modulo input terminals  
34 M\_IN[7:0], incrementer 2105 increments the value provided on  
35 modulo input terminals M\_IN[7:0] by one to generate modulo  
36 value M, which is provided to a first input port of  
37 multiplier 2110. Other embodiments of the present invention  
38 may receive modulo value M on modulo input terminals  
39 M\_IN[7:0]. These embodiments would not require incrementer  
40 2105. A second input port IN2 of multiplier 2110 is coupled  
41 to an output terminal of comparator 2160. Multiplier 2110

1       multiples the value provided on modulo input terminals  
2       M\_IN[7:0] by the output value of comparator 2160 to generate  
3       an output product, which is provided to a second input port  
4       IN2 of subtracter 2120. In many embodiments of the present  
5       invention, multiplier 2110 is implemented using a plurality  
6       of AND gates, because the output value of comparator 2160 is  
7       a single bit.

8       Pulse input terminals P\_IN[7:0] are coupled to a first  
9       input terminal of subtracter 2120. Subtractor 2120 is  
10      configured to subtract the output value from multiplier 2110  
11      from the pulse value provided on pulse input terminals  
12      P\_IN[7:0] to generate a delta value DELTA on output port OUT  
13      of subtracter 2120. Output port OUT of subtracter 2120 is  
14      coupled to a first input port IN1 of adder 2130. A second  
15      input port IN2 of adder 2130 is coupled to an output port  
16      OUT of latch 2150. Adder 2130 is configured to add delta  
17      value DELTA provided by subtracter 2120 to a latch value  
18      LATCH provided by latch 2150 to generate a sigma value SIGMA  
19      on output port OUT of adder 2130. Output port OUT of adder  
20      2130 is coupled to a first input port IN1 of multiplexing  
21      circuit 2140. Some embodiments of the present invention  
22      calculate sigma value SIGMA using a sigma calculation  
23      circuit, such as a three input adder, which can perform the  
24      calculation faster than using a separate delta calculation  
25      circuit, such as subtracter 2120. In these embodiments the  
26      sigma calculation circuit replaces subtracter 2120 and adder  
27      2130. For embodiments using a three input adder, the output  
28      value of multiplier 2110 can be converted into a 2's  
29      complement format prior to the three input adder.  
30      Furthermore, incrementer 2105 and multiplier 2110 may be  
31      combined within a circuit to compute the 2's complement  
32      format.

33      Multiplexing circuit 2140 is configured to drive either  
34      sigma value SIGMA or the value provided on modulo input  
35      terminals M\_IN[7:0] to input port IN of latch 2150 through  
36      output port OUT of multiplexing circuit 2140. Reset

1 terminal RESET is coupled to a control terminal of  
2 multiplexing circuit 2140. Pre-concurrence signal PRE\_CONC,  
3 which is coupled to reset terminal RESET in Fig. 20,  
4 determines the output value of multiplexing circuit 2140.  
5 Specifically, during the clock cycle before concurrences  
6 multiplexing circuit 2140 is configured to drive the value  
7 provided on modulo input terminals M\_IN[7:0] to input port  
8 IN of latch 2150. Otherwise, multiplexing circuit 2140 is  
9 configured to drive sigma value SIGMA to input port IN of  
10 latch 2150. Latch 2150, which is clocked by control clock  
11 signal CTRL\_CLK, provides a LATCH value on output port OUT  
12 of latch 2150 to a first input port IN1 of comparator 2160.  
13 Comparator 2160, which is configured to compare latch value  
14 LATCH with the value provided on modulo input terminals  
15 M\_IN[7:0], generates fine tuning increment signal FT\_INC on  
16 output terminal OUT of comparator 2160. Specifically, if  
17 latch value LATCH is greater than the modulo value provided  
18 on modulo input terminals M\_IN[7:0], fine tuning increment  
19 signal FT\_INC is driven to the active logic level (e.g.,  
20 logic high). Otherwise, fine tuning increment signal FT\_INC  
21 is driven to the inactive logic level (e.g., logic low).

22 Table 4 provides a pseudo code implementation of a  
23 second embodiment of modulo-M delta sigma circuit 2030. One  
24 skilled in the art of digital design can convert the pseudo  
25 code of Table 4 to a hardware definition language such as  
26 Verilog to implement the circuit.

28 TABLE 4

29  
30     DELTA = P - (FT\_INC \* M)  
31     SIGMA = DELTA + LATCH  
32     IF RESET then LATCH=(M-1)  
33         else LATCH=SIGMA  
34     IF LATCH > (M-1) then FT\_INC = 1  
35         else FT\_INC = 0

36  
37     As explained above, one embodiment of the present  
38 invention operates digital frequency synthesizer 1400 in

1 three distinct phases. Specifically, digital frequency  
2 synthesizer 1400 is operated in a coarse frequency search  
3 phase, a fine frequency search phase, and a clock  
4 maintenance phase. During the coarse frequency search  
5 phase, variable delay line 1520 (Fig. 15) is configured  
6 using the fast binary search as described above. Delay line  
7 fine tuning controller 1720 (Fig. 17) is disabled during the  
8 coarse frequency search phase. The coarse frequency search  
9 phase ends when right shifter 1830 (Fig. 18) contains a  
10 value of one.

11 During the fine frequency search phase, delay line fine  
12 tuning controller 1720 is activated and clock selector 1430  
13 (Fig. 14) is configured to select frequency adjusted clock  
14 signal FREQ\_CLK as the control clock signal CTRL\_CLK.  
15 During the fine frequency search phase, delay line fine  
16 tuning controller 1720 is controlled by frequency comparator  
17 1850 (Fig. 18) using control signal A/!S as described above.  
18 Specifically, control signal A/!S determines whether up/down  
19 counter 2020 increments or decrements. Halt/restart circuit  
20 1445 is also used in the fine frequency search phase during  
21 each concurrence period. In the fine frequency search  
22 phase, up/down counter 2020 increments or decrements by one  
23 each concurrence period. As explained above, up/down  
24 counter 2020 is linked to delay line register 1710 by carry  
25 signal CARRY and borrow signal BORROW. Thus, the value in  
26 delay line register 1710 may change during the fine  
27 frequency search phase. The fine frequency search phase  
28 ends when frequency comparator 1850 detects a reversal and  
29 drives frequency comparator reversal signal to the active  
30 state.

31 During the clock maintenance phase, phase comparator  
32 1440 (Fig. 14) takes control of oscillator control circuit  
33 1460 from initialization circuit 1450. During the  
34 maintenance phase, delay line fine tuning controller 1720 is  
35 selectively enabled. Specifically, in one embodiment of the  
36 present invention, the maintenance phase cycles through

1 three sub-phases. Each sub-phase lasts for one concurrence  
2 period. In the first sub-phase, phase comparator 1440 is  
3 initialized. During the first sub-phase the value of  
4 up/down counter 2020 does not change. In the second sub-  
5 phase phase comparator 1440 determines whether feedback  
6 clock signal FBK\_CLK leads or lags divided synchronizing  
7 clock signal D\_SYNCH\_CLK. In the third sub-phase delay line  
8 fine tuning controller 1720 is enabled. Thus, up/down  
9 counter 2020 can increment or decrement by one as controlled  
10 by phase comparator control signal PC\_CTRL. As explained  
11 above phase comparator control signal PC\_CTRL indicates  
12 whether feedback clock signal FBK\_CLK leads or lags divided  
13 synchronizing clock signal D\_SYNCH\_CLK. If delayed  
14 synchronizing clock signal D\_SYNCH\_CLK leads feedback clock  
15 signal FBK\_CLK, then phase comparator 1440 causes up/down  
16 counter 2020 to decrement during the second sub-phase.  
17 Otherwise, phase comparator 1440 causes up/down counter 2020  
18 to increment during the second sub-phase. In other  
19 embodiments, the maintenance phase may include more or fewer  
20 sub-phases. For example, in one embodiment, the first sub-  
21 phase and the second sub-phase described above are combined  
22 into a single sub-phase. Some embodiments of the present  
23 invention wait until phase comparator 1440 detects multiple  
24 reversals (such as four reversals) before declaring  
25 frequency adjusted clock signal FREQ\_CLK is at selected  
26 frequency F\_SEL.

27 In the various embodiments of the present invention,  
28 novel structures have been described for digital clock  
29 managers. By using a synchronizing clock signal with  
30 matched output delays, the present invention can provide  
31 deskewed output clock signals with synchronized frequency  
32 adjusted clock signals. The various embodiments of the  
33 structures and methods of this invention that are described  
34 above are illustrative only of the principles of this  
35 invention and are not intended to limit the scope of the  
36 invention to the particular embodiments described. For

1 example, in view of this disclosure those skilled in the art  
2 can define other delay lock loops, output generation  
3 circuits, output delays, variable delay circuits, digital  
4 frequency synthesizers, clock phase shifters, delay lines,  
5 output generators, controllers, phase detectors, latches,  
6 registers, clock dividers, phase comparators, frequency  
7 comparators, up/down counters, initialization circuits,  
8 delta-sigma circuits, latches, halt/restart circuits, delay  
9 lines, variable digital oscillators, edge-triggered SR  
10 circuits, active edges, enable logic levels, and so forth,  
11 and use these alternative features to create a method,  
12 circuit, or system according to the principles of this  
13 invention. Thus, the invention is limited only by the  
14 following claims.

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